Search Notes				

Application/Control No.	Applicant(s)/Patent und Reexamination	ler
10/697,558	HAYASHI ET AL.	
Examiner	Art Unit	
Sophia S. Chen	2852	

SEARCHED				
Class	Subclass	Date	Examiner	
Class	Subclass	Date	Examiner	
399	258, 262, 260, 120, 119	3/22/2005	sc	
222	DIG.1	3/22/2005	sc	
above	updated	8/22/2005	sc	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
Interfered History Pr	ice Search	8/22/2005	sc	
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Text Search (see printout)	3/22/2005	SC
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